

DEVELOPMENT OF CRYSTALLOGRAPHIC PROCESS TECHNOLOGY FOR PIEZOELECTRIC ACTUATOR FOR BIO-MEMS DEVICE

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Abstract. Recently, the lead free piezoelectric material, which could be used for the actuator and the sensor of medical care devices, such as the health monitoring system (HMS) and the drug delivery system (DDS), is strongly required. In this study, we try to find a new biocompatible and lead-free piezoelectric material, by using the three-scale process-crystallographic analyses scheme, which consists of the first-principles calculations, the homogenization based finite element method, and the process optimization algorithm. After numerical calculations, we found an optimum biocompatible element combination and a tetragonal crystal structure of candidate material MgSiO_3 . As a result of process crystallography simulation to adjust with the selected substrate $\text{Au}(111)$, lattice parameters of MgSiO_3 with tetragonal structure were obtained as $a=b=0.3449\text{nm}$ and $c=0.3538\text{nm}$, and its aspect ratio was 1.026. The piezoelectric stress constants of a non constraint MgSiO_3 crystal, $e_{33}=4.57\text{C/m}^2$, $e_{31}=-2.20\text{C/m}^2$ and $e_{15}=12.77\text{C/m}^2$, were obtained. Macro homogenized piezoelectric stress constants of MgSiO_3 thin film were obtained as $e_{33}=5.10\text{C/m}^2$, $e_{31}=-3.65\text{C/m}^2$ and $e_{15}=3.24\text{C/m}^2$. We confirmed the availability of our process crystallographic simulation scheme for a new biocompatible piezoelectric material design through the comparison with the experimental observation of a newly generated MgSiO_3 thin film material.

1 INTRODUCTION

Recently, the lead-based piezoelectric materials, such as PbTiO_3 and $\text{Pb}(\text{Zr,Ti})\text{O}_3$, have been applied to various actuators [1] and sensors [2] in Micro Electro Mechanical System (MEMS) devices due to their high piezoelectric and dielectric properties. However, these materials contain the lead. Recently, lead and hazardous material are prohibited to use by Restriction of Hazardous Substances (RoHS) regulation [3]. Recently, the lead-free and biocompatible piezoelectric materials for Bio-MEMS devices have been developed by using the computational and the experimental approaches [4].

Zhang S. et al. [5] doped Ca and Zr in BaTiO_3 and succeeded in generating the piezoelectric material with high piezoelectric and dielectric constants. Fu P. et al. [6] doped La_2O_3 in Bi based $(\text{Bi}_{0.5}\text{Na}_{0.5})_{0.94}\text{Ba}_{0.06}\text{TiO}_3$ and succeeded in generating the piezoelectric

material with high piezoelectric constant and spontaneous polarization. However, these materials had problem of biocompatibility, and were not adequate for Bio-MEMS devices. Especially, ions of the composition element of a piezoelectric material invade the human body, when piezoelectric materials are applied to the implanted Bio-MEMS device. Therefore, piezoelectric materials should be constructed by biocompatible elements.

In previous study, we have developed a new three-scale analysis algorithm for a new piezoelectric material design, which consists of the first-principles calculation [7] and the process-crystallographic analyses scheme [8]. MgSiO_3 , which was a candidate for a new biocompatible piezoelectric material and had the perovskite tetragonal structure, was found by using this numerical scheme, and it showed a high piezoelectric constant. Before a new material MgSiO_3 design and generation, we confirm the availability of our newly developed simulation scheme to analyze the epitaxial growth process of the perovskite tetragonal crystal structure and the piezoelectric properties of the existence piezoelectric material BaTiO_3 . Numerical results showed a good agreement with the experimental ones.

In this study, we apply our three-scale process-crystallographic analyses scheme to design a new biocompatible MgSiO_3 piezoelectric thin film. Then, this thin film is generated by using the radio-frequency (RF) magnetron sputtering. Finally, the crystallographic orientation and the piezoelectric strain constant d_{33} are measured by using the X-ray diffractometer (XRD) and the ferroelectric measurement system to confirm the availability of our process-crystallographic design algorithm.

2 FIRST-PRINCIPLES AIDED THREE-SCALE ANALYSIS

2.1 Three-scale modeling of a piezoelectric thin film

Figure 1 shows the schematic description of the first-principles aided three-scale modeling of the piezoelectric thin film, which is grown on a substrate. It shows the three-scale structures, such as a “crystal structure”, a “micro structure” and a “macro structure.”

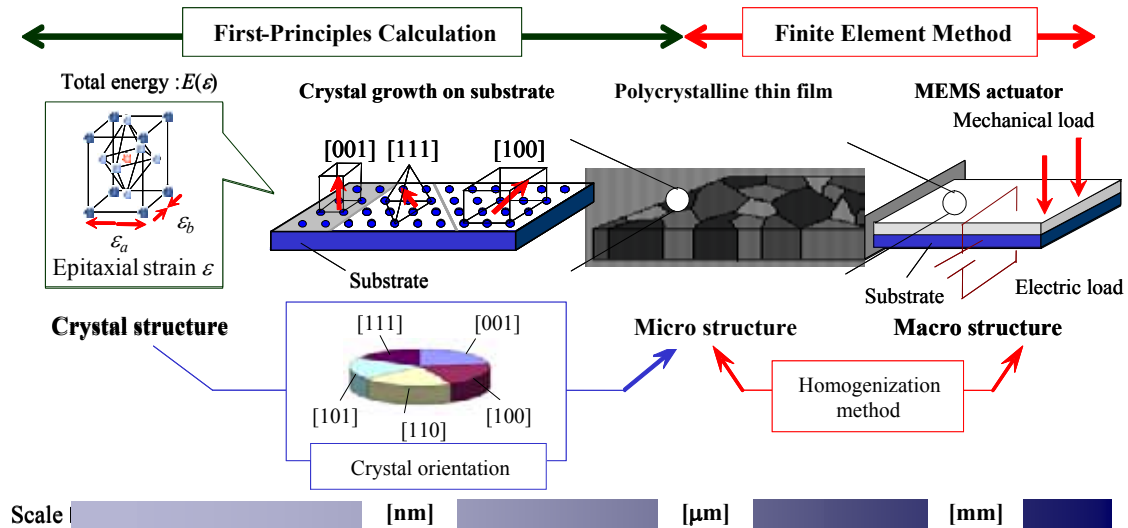


Figure 1: First-principles aided three-scale modeling of piezoelectric thin film on substrate

In the crystal structure scale, the stable structure and the crystal properties are evaluated by using the first-principles calculation. Next, the preferred orientations and their fractions are determined by considering the epitaxial strains, caused by the lattice mismatches between the thin film and the substrates. Additionally, the calculated crystal morphology is introduced into the micro structure and properties of the macro structure, which consist the thin film and the substrate, are calculated by the two-scale finite element analysis, which is derived based on the homogenization theory.

2.2 Process crystallography simulation algorithm

Thin film crystal is strained by mismatch between lattice constant of thin film and one of substrate, when thin film is grown epitaxially. Virtual crystal clusters with various orientations and conformations are generated by our process crystallography simulation, because thin film crystal has various conformations on a substrate as shown in Figure 2(a) and (b). Total energies of virtual clusters are varied by the crystal strain. Therefore, total energies of strained crystals are calculated by using the density functional theory (DFT), and total energies of virtual clusters are calculated. Total energies of virtual clusters are compared with one of stable state and total energy increments of virtual crystals are also calculated. In order to calculate the possibility of growth of the virtual cluster P_i , total energy increment ΔE is introduced into the canonical distribution as flows:

$$P_i = \frac{\exp[\Delta E_i/k_B T]}{\sum_n \exp[\Delta E_n/k_B T]} \quad (1)$$

where, k_B is the Boltzmann constant and T the absolute temperature.

The existing lead-free BaTiO_3 piezoelectric material with (111) orientation, which has perovskite type tetragonal structure as same as MgSiO_3 , shows highest piezoelectric properties. In this study, we find the best substrate of $\text{MgSiO}_3(111)$ with the minimum energy is found.

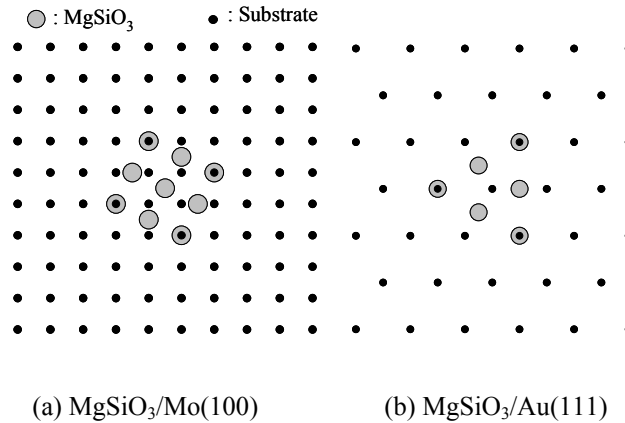


Figure 2: Schematic diagram for some conformations of MgSiO_3 crystal cluster on substrates

2.3 Numerical characterization process of the macro homogenized piezoelectric thin film

In order to evaluate the macro homogenized properties of the thin film, the micro structure of the thin film with a preferred orientation is applied to the two-scale finite element analysis on basis of crystallographic homogenization theory as shown in Fig.1. The crystal orientation fraction of the thin film is determined by frequency distribution of each grown cluster, which is calculated by the canonical distribution. The crystal orientation is introduced in the micro structure. For simplicity, the micro structure is divided evenly by eight-node rectangular solid elements and crystal orientations are assigned at the integration points of each element. For BaTiO₃, we employ experimentally obtained properties in the micro structure, and for MgSiO₃, computational properties obtained by the first-principles are employed for the micro structure.

3 DESIGN OF A NEW BIOCOMPATIBLE MATERIAL

3.1 The first-principles calculation

To calculate the crystal structure of perovskite MgSiO₃, energy cutoff was set as 500eV and k-point was generated by 8×8×8 Monkhorst-Pack mesh. We calculated the cubic structure as shown in Figure 3. Lattice constants $a=b=c=0.3459\text{nm}$ were obtained.

The eigenfrequency of the cubic structure of MgSiO₃ was obtained as -112cm^{-1} by using phonon vibration analysis. This result indicated that MgSiO₃ crystal had possibility of phase transition to another phase, due to the eigenfrequency with negative value. Table I shows eigenvectors of each atom. It indicated that MgSiO₃ cubic crystal had possibility to change to the tetragonal structure, because all eigenvectors were existed along c axis only.

In order to calculate the stable tetragonal structure, initial structure was determined by employing eigenvectors. As a result, lattice parameters were obtained as $a=b=0.3449\text{nm}$ and $c=0.3538\text{nm}$. The aspect ratio $a/c=1.026$ was obtained from 1.011 of BaTiO₃ thin film [9] to 1.049 of PbTiO₃ thin film [10]. Table 2 shows internal coordinates of the tetragonal MgSiO₃. We obtained reasonable result, because displacements of all internal atoms of the tetragonal structure had good agreement with direction of eigenvectors of the cubic structure as show in Table 1.

Furthermore, the variation of polarization and piezoelectricity of MgSiO₃ caused by the assigned small strain was calculated. The piezoelectric stress constants of MgSiO₃ crystal were determined as $e_{33}=4.57\text{C/m}^2$, $e_{31}=-2.20\text{C/m}^2$ and $e_{15}=12.77\text{C/m}^2$.

3.2 Determination of the best substrate

Biocompatible elements have bio-essential elements (Ca, Fe, Ge, Mg, Mn, Mo, Na, Ni, Sn and Zn) and elements (Si, Ta, Ti and Zr), which have been used in the human body. In previous study, we calculated reactivity with biological molecules and found new biocompatible elements (Li, Ba, K, Au, Rb, In) [11]. In these 20 biocompatible elements, we selected Au, Mo and Ta for candidates of the substrate, because these elements satisfied four terms, such as (1) the melting point is over sputtering temperature, (2) element dose not react to other elements under sputtering condition, (3) element is able to be use the under electrode and (4) element is cubic structure. Lattice parameters of Au with FCC cubic structure are

$a=b=c=0.4080\text{nm}$, ones of Mo with BCC cubic structure are $a=b=c=0.3147\text{nm}$ and ones of Ta with BCC cubic structure are $a=b=c=0.3289\text{nm}$.

Table 3 shows result of crystallography simulation on (100), (110) and (111) oriented three substrate candidates. Total energies and orientation fractions of epitaxially grown MgSiO_3 thin films were different depend on conformations as shown in Figure 4. It shows an example of conformations of $\text{MgSiO}_3(001)/\text{Au}(100)$.

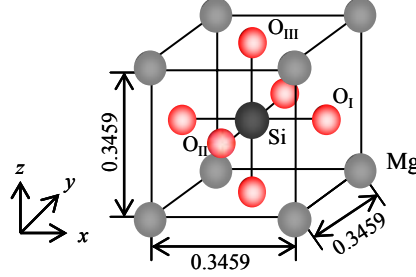


Figure 3: Schematic diagram for some conformations of MgSiO_3 crystal cluster on substrates

Table 1: Eigenvectors of interior atoms in MgSiO_3 Crystal

Atom	Eigenvector		
	ξ_x	ξ_y	ξ_z
Mg	0.00	0.00	0.88
Si	0.00	0.00	-0.13
O _I	0.00	0.00	-0.37
O _{II}	0.00	0.00	-0.37
O _{III}	0.00	0.00	-0.22

Table 2: Internal coordinates of MgSiO_3 crystal

Atom	x	y	z
Mg	0.00	0.00	0.00
Si	0.50	0.50	0.42
O _I	0.00	0.50	0.38
O _{II}	0.50	0.00	0.38
O _{III}	0.50	0.50	0.90

Table 3: Internal coordinates of MgSiO_3 crystal

Substrate		MgSiO_3		
Atom	Facet	Facet	Energy [eV]	Fraction [%]
Au	(100)	(001)	0.075	87.7
		(001)	0.126	12.3
	(110)	(101)	0.343	92.0
		(101)	0.406	8.0
	(111)	(111)	0.539	100.0
		(111)	0.539	100.0
Mo	(100)	(100)	0.093	61.5
		(001)	0.105	38.5
	(110)	(001)	0.254	70.1
		(001)	0.287	20.2
	(111)	(101)	0.305	9.7
		(111)	0.774	100.0
Ta	(100)	(001)	0.001	90.8
		(001)	0.061	9.1
	(110)	(001)	0.172	0.1
		(101)	0.329	99.8
	(111)	(101)	0.488	0.2
		(101)	0.929	100.0

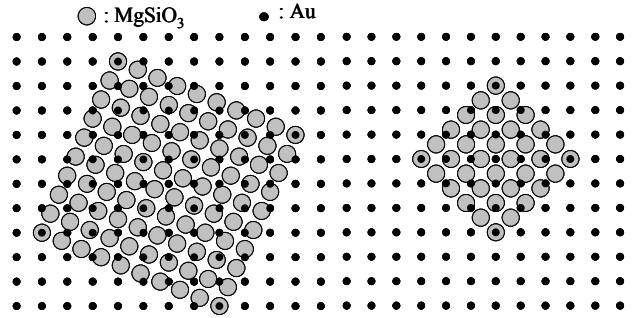


Figure 4: Conformations of MgSiO₃/Au(100) calculated by process crystallography simulation

Therefore, we summarized numerical results of independent orientations, total energies and fractions in Table 3. It shows that MgSiO₃(111) with highest piezoelectric property could be grown on Au(111) and Mo(111) substrates. Here, Au(111) was the best substrate of biocompatible MgSiO₃ thin film, because the total energy of MgSiO₃ on Au(111) was smaller than one on Mo(111) substrate.

Finally, the macro homogenized piezoelectric property of MgSiO₃ thin film on the best substrate, Au(111), was calculated by using the two-scale finite element analysis on basis of crystallographic homogenization theory. As a result, macro homogenized piezoelectric stress constants were calculated as $e_{33}=5.10\text{C/m}^2$, $e_{31}=-3.65\text{C/m}^2$ and $e_{15}=3.24\text{C/m}^2$.

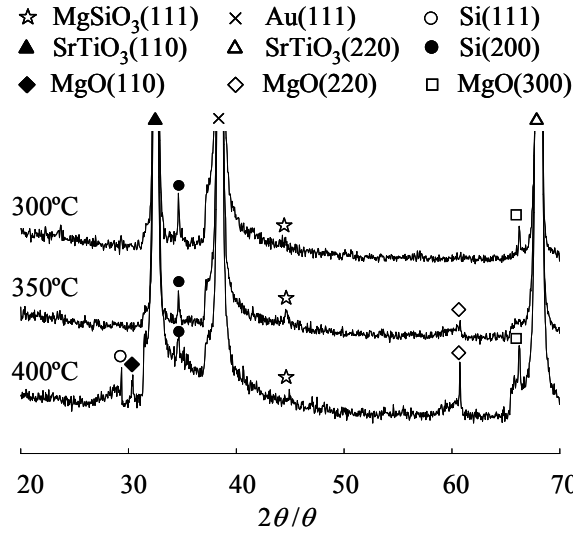


Figure 5: XRD $2\theta/\theta$ patterns for MgSiO₃ thin films generated at $T_d=650^\circ\text{C}$ and $T_s=300, 350$ and 400°C

4 EXPERIMENTAL RESULTS OF THIN FILM GENERATION BY SPUTTERING

In order to confirm the availability of our process-crystallographic simulation scheme, MgSiO₃ thin film with the perovskite tetragonal crystal structure was generated by using RF

magnetron sputtering apparatus. We employed the simple search algorithm, such as the experimental design algorithm, by employing two design parameters, such as the substrate temperature T_s and post annealing temperature T_a .

Figure 5 shows $2\theta/\theta$ patterns for MgSiO_3 thin film generated at $T_a=650^\circ\text{C}$ and $T_s=300, 350$ and 400°C . The peak of $\text{MgSiO}_3(111)$ crystal was obtained.

The displacement-voltage curves were measured by using the ferroelectric measurement system in six cases of combinations with $T_a=600, 650$ and 700°C and $T_s=300$ and 350°C . Figure 6 shows displacement-voltage curves of generated piezoelectric MgSiO_3 thin films. It means that all films showed the piezoelectric property because of typical butterfly-type hysteresis curves. The piezoelectric strain constant d_{33} can be calculated by the gradient at cross point of the curve. Figure 7 shows measurement results of d_{33} under conditions of $T_s=300, 350$ and 400°C , and $T_a=650^\circ\text{C}$.

Finally, the optimum condition, $T_s=300^\circ\text{C}$ and $T_a=650^\circ\text{C}$, was found and the piezoelectric strain constant was $d_{33}=346.7\text{pm/V}$.

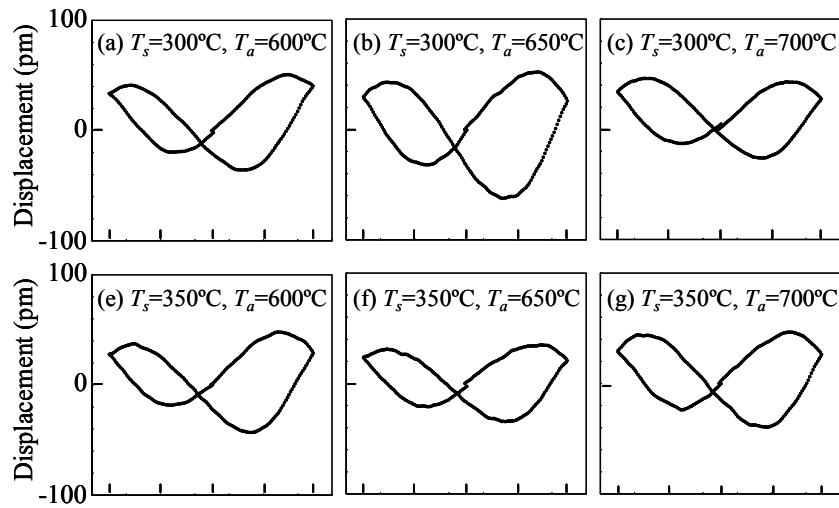


Figure 6: Displacement-voltage curves of MgSiO_3 thin film

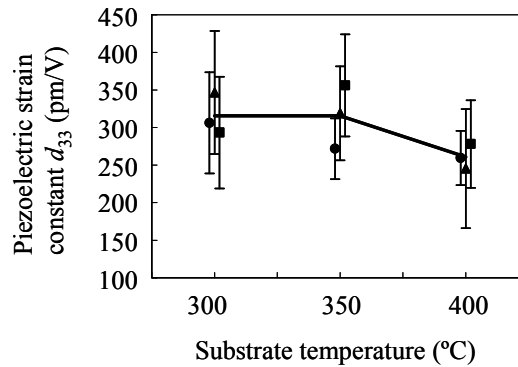


Figure 7: Relationship between piezoelectric strain constant d_{33} and substrate temperature under the condition of the post-anneal temperature 650°C

5 CONCLUSION

In order to generate a new biocompatible MgSiO_3 piezoelectric thin film, which can apply to the Bio-MEMS device, our three-scale process-crystallographic simulation scheme for a new material generation was applied. Further, MgSiO_3 was generated by using RF magnetron sputtering apparatus and confirm the availability of our simulation scheme through the comparison with the experimental results. Finally, following results were obtained.

- (1) Lattice constants of MgSiO_3 with tetragonal structure were obtained as $a=b=0.3449\text{nm}$ and $c=0.3538\text{nm}$, and its aspect ratio is 1.026.
- (2) The piezoelectric stress constants of MgSiO_3 crystal, $e_{33}=4.57\text{C/m}^2$, $e_{31}=-2.20\text{C/m}^2$ and $e_{15}=12.77\text{C/m}^2$, were obtained.
- (3) Au(111) was the best biocompatible substrate, on which $\text{MgSiO}_3(111)$ thin film with minimum total energy can be grown.
- (4) Macro homogenized piezoelectric stress constants of MgSiO_3 thin film on Au(111) substrate were obtained as $e_{33}=5.10\text{C/m}^2$, $e_{31}=-3.65\text{C/m}^2$ and $e_{15}=3.24\text{C/m}^2$.
- (5) An optimum condition was obtained as $T_s=300^\circ\text{C}$ and $T_a=650^\circ\text{C}$, and its piezoelectric strain constant was $d_{33}=346.7\text{pm/V}$.

Consequently, we indicated that a new biocompatible MgSiO_3 thin film could be applied to actuators and sensors in Bio-MEMS.

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